

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 21.0002

CB Certificate No.: 50600386 ITL

Schedule Number: IECQ-L ULTW 21.0002-S Rev No.: 4 Revision Date: 2024/01/08 Page 1 of 1

Appendix-1 (50600386 ITL) Schedule of Scope to Certificate of Approval

| Test Items | Standard/Method |
|--|-----------------------------|
| Scanning Electron Microscope (SEM) Analysis | TE3-F01 |
| Bonding Strength Test | JESD22-B115 and JESD22-B117 |
| 銲點結合力試驗 | TE3-M01 |
| High Temperature Storage Life | JESD22-A103 |
| 高溫储存試驗 | TE3-R01 |
| Temperature Cycling Test (TCT) | JESD-A104 |
| 溫度循環試驗 | TE3-R06 |
| Temperature and Humidity Storage Test (THT) 溫濕度儲存試驗 | TE3-R08 |
| Halide Content Test | JIS-Z-3197 8.1.4.2 |
| 鹵化物含量試驗 | TE3-C01 |
| Acid Value Test | JIS-Z-3197 8.1.4.1, |
| 酸價試驗 | TE3-C02 |
| Surface Insulation Resistance | IPC-TM-650 2.6.3.7 |
| 表面絕緣阻抗試驗 | TE3-R03 |
| Electrochemical Migration Resistance Test | IPC-TM-650 2.6.14.1 |
| 電子遷移試驗 | TE3-R05 |
| Corrosion, Flux | IPC-TM-650 2.6.15 |
| 銅板腐蝕試驗 | TE3-R04 |
| Dye and Pull Test | IPC-TM-650 2.4.53 |
| 紅墨水試驗 | TE3-F03 |

Technical Reviewer of DQS:

Date: 01/08/2024



